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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

#### Applications of "[Embedded - Microcontrollers](#)"

##### Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	I²C, IrDA, LINbus, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, I²S, LCD, POR, PWM, WDT
Number of I/O	75
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	64K x 8
Voltage - Supply (Vcc/Vdd)	1.68V ~ 3.6V
Data Converters	A/D 15x12b; D/A 1x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-TQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/microchip-technology/atsam4lc8ca-aur">https://www.e-xfl.com/product-detail/microchip-technology/atsam4lc8ca-aur</a>

## 3.2 Peripheral Multiplexing on I/O lines

### 3.2.1 Multiplexed Signals

Each GPIO line can be assigned to one of the peripheral functions. The following tables (Section 3-1 "100-pin GPIO Controller Function Multiplexing" on page 19 to Section 3-4 "48-pin GPIO Controller Function Multiplexing" on page 28) describes the peripheral signals multiplexed to the GPIO lines.

Peripheral functions that are not relevant in some parts of the family are grey-shaded.

For description of different Supply voltage source, refer to the [Section 6. "Power and Startup Considerations" on page 46](#).

**Table 3-1.** 100-pin GPIO Controller Function Multiplexing (Sheet 1 of 4)

ATSAM4LC		ATSAM4LS		Pin	GPIO	Supply	GPIO Functions						
QFN	VFBGA	QFN	VFBGA				A	B	C	D	E	F	G
5	B9	5	B9	PA00	0	VDDIO							
6	B8	6	B8	PA01	1	VDDIO							
12	A7	12	A7	PA02	2	VDDIN	SCIF GCLK0	SPI NPCS0					CATB DIS
19	B3	19	B3	PA03	3	VDDIN		SPI MISO					
24	A2	24	A2	PA04	4	VDDANA	ADCIFE AD0	USART0 CLK	EIC EXTINT2	GLOC IN1			CATB SENSE0
25	A1	25	A1	PA05	5	VDDANA	ADCIFE AD1	USART0 RXD	EIC EXTINT3	GLOC IN2	ADCIFE TRIGGER		CATB SENSE1
30	C3	30	C3	PA06	6	VDDANA	DACC VOUT	USART0 RTS	EIC EXTINT1	GLOC IN0	ACIFC ACAN0		CATB SENSE2
31	D3	31	D3	PA07	7	VDDANA	ADCIFE AD2	USART0 TXD	EIC EXTINT4	GLOC IN3	ACIFC ACAP0		CATB SENSE3
44	G2	44	G2	PA08	8	LCDA	USART0 RTS	TC0 A0	PEVC PAD EVT0	GLOC OUT0		LCDCA SEG23	CATB SENSE4
47	F5	47	F5	PA09	9	LCDA	USART0 CTS	TC0 B0	PEVC PAD EVT1	PARC PCDATA0		LCDCA COM3	CATB SENSE5
48	H2	48	H2	PA10	10	LCDA	USART0 CLK	TC0 A1	PEVC PAD EVT2	PARC PCDATA1		LCDCA COM2	CATB SENSE6
49	H3	49	H3	PA11	11	LCDA	USART0 RXD	TC0 B1	PEVC PAD EVT3	PARC PCDATA2		LCDCA COM1	CATB SENSE7
50	J2	50	J2	PA12	12	LCDA	USART0 TXD	TC0 A2		PARC PCDATA3		LCDCA COM0	CATB DIS
63	H5	63	H5	PA13	13	LCDA	USART1 RTS	TC0 B2	SPI NPCS1	PARC PCDATA4		LCDCA SEG5	CATB SENSE8
64	K7	64	K7	PA14	14	LCDA	USART1 CLK	TC0 CLK0	SPI NPCS2	PARC PCDATA5		LCDCA SEG6	CATB SENSE9
65	G5	65	G5	PA15	15	LCDA	USART1 RXD	TC0 CLK1	SPI NPCS3	PARC PCDATA6		LCDCA SEG7	CATB SENSE10

**Table 3-4.** 48-pin GPIO Controller Function Multiplexing (Sheet 2 of 2)

ATSAM4LC	ATSAM4LS	Pin	GPIO	Supply	GPIO Functions						
					A	B	C	D	E	F	G
44	44	PA24	24	LCDC	SPI NPCS0	TWIMS0 TWCK		GLOC OUT0	SCIF GCLK IN1	LCDCA SEG39	CATB SENSE18
46	46	PA25	25	VDDIO	USBC DM	USART2 RXD					CATB SENSE19
47	47	PA26	26	VDDIO	USBC DP	USART2 TXD					CATB SENSE20
	25	PA27	27	LCDA	SPI MISO	IISC ISCK	ABDACB DAC0	GLOC IN4	USART3 RTS		CATB SENSE0
	26	PA28	28	LCDA	SPI MOSI	IISC ISDI	ABDACB DACP0	GLOC IN5	USART3 CTS		CATB SENSE1
	27	PA29	29	LCDA	SPI SCK	IISC IWS	ABDACB DACP1	GLOC IN6	USART3 CLK		CATB SENSE2
	30	PA30	30	LCDA	SPI NPCS0	IISC ISDO	ABDACB DACP1	GLOC IN7	USART3 RXD		CATB SENSE3
	31	PA31	31	LCDA	SPI NPCS1	IISC IMCK	ABDACB CLK	GLOC OUT1	USART3 TXD		CATB DIS

### 3.2.2 Peripheral Functions

Each GPIO line can be assigned to one of several peripheral functions. The following table describes how the various peripheral functions are selected. The last listed function has priority in case multiple functions are enabled on the same pin.

**Table 3-5.** Peripheral Functions

Function	Description
GPIO Controller Function multiplexing	GPIO and GPIO peripheral selection A to H
JTAG port connections	JTAG debug port
Oscillators	OSC0

### 3.2.3 JTAG Port Connections

If the JTAG is enabled, the JTAG will take control over a number of pins, irrespectively of the I/O Controller configuration.

**Table 3-6.** JTAG Pinout

48-pin Packages	64-pin QFP/QFN	64-pin WLSCP	100-pin QFN	100-ball VFBGA	Pin Name	JTAG Pin
10	10	E2	19	B3	PA03	TMS
43	59	H3	95	D6	PA23	TDO
44	60	G3	96	D10	PA24	TDI
9	9	F2	18	B4	TCK	TCK

## 5.2 Embedded Memories

- Internal high-speed flash
  - 512Kbytes (ATSAM4Lx8)
  - 256Kbytes (ATSAM4Lx4)
  - 128Kbytes (ATSAM4Lx2)
  - Pipelined flash architecture, allowing burst reads from sequential flash locations, hiding penalty of 1 wait state access
  - Pipelined flash architecture typically reduces the cycle penalty of 1 wait state operation compared to 0 wait state operation
  - 100 000 write cycles, 15-year data retention capability
  - Sector lock capabilities, bootloader protection, security bit
  - 32 fuses, erased during chip erase
  - User page for data to be preserved during chip erase
- Internal high-speed SRAM, single-cycle access at full speed
  - 64Kbytes (ATSAM4Lx8)
  - 32Kbytes (ATSAM4Lx4, ATSAM4Lx2)

## 5.3 Physical Memory Map

The system bus is implemented as a bus matrix. All system bus addresses are fixed, and they are never remapped in any way, not even during boot. The 32-bit physical address space is mapped as follows:

**Table 5-1.** ATSAM4L8/L4/L2 Physical Memory Map

Memory	Start Address	Size	Size
		ATSAM4Lx4	ATSAM4Lx2
Embedded Flash	0x00000000	256Kbytes	128Kbytes
Embedded SRAM	0x20000000	32Kbytes	32Kbytes
Cache SRAM	0x21000000	4Kbytes	4Kbytes
Peripheral Bridge A	0x40000000	64Kbytes	64Kbytes
Peripheral Bridge B	0x400A0000	64Kbytes	64Kbytes
AESA	0x400B0000	256 bytes	256 bytes
Peripheral Bridge C	0x400E0000	64Kbytes	64Kbytes
Peripheral Bridge D	0x400F0000	64Kbytes	64Kbytes

Memory	Start Address	Size
		ATSAM4Lx8
Embedded Flash	0x00000000	512Kbytes
Embedded SRAM	0x20000000	64Kbytes
Cache SRAM	0x21000000	4Kbytes
Peripheral Bridge A	0x40000000	64Kbytes
Peripheral Bridge B	0x400A0000	64Kbytes

## 6. Power and Startup Considerations

### 6.1 Power Domain Overview

**Figure 6-1.** ATSAM4LS Power Domain Diagram

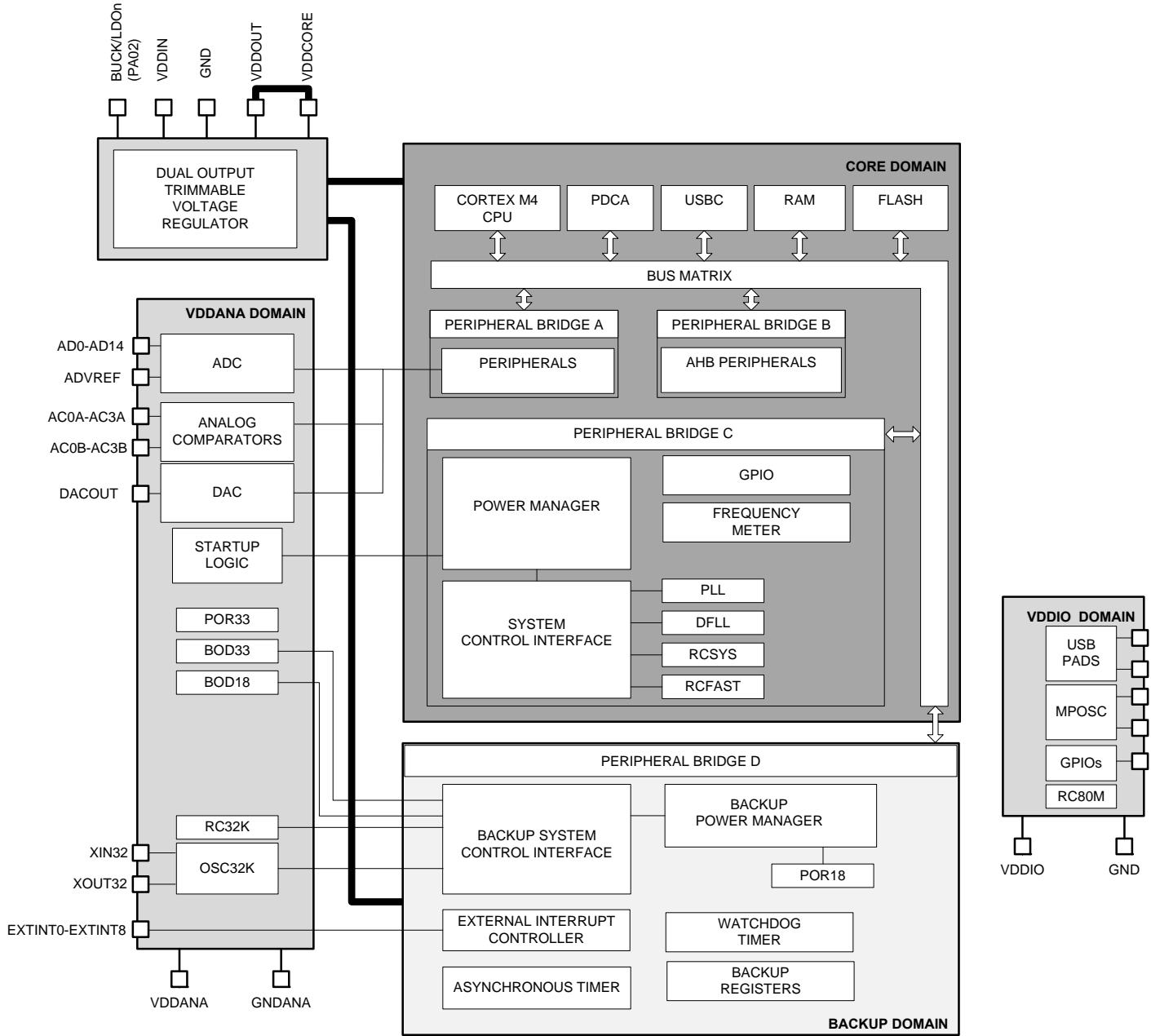
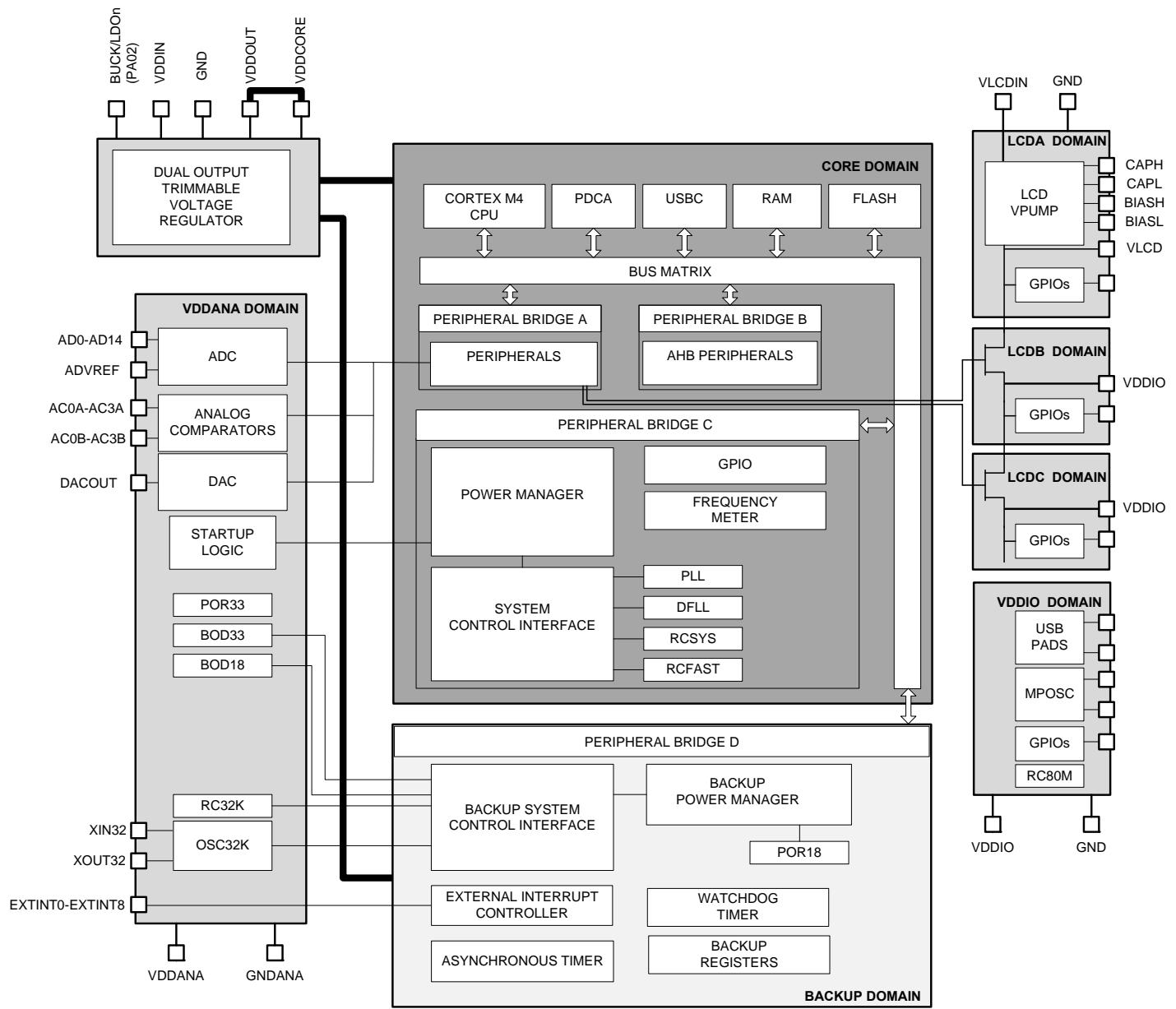
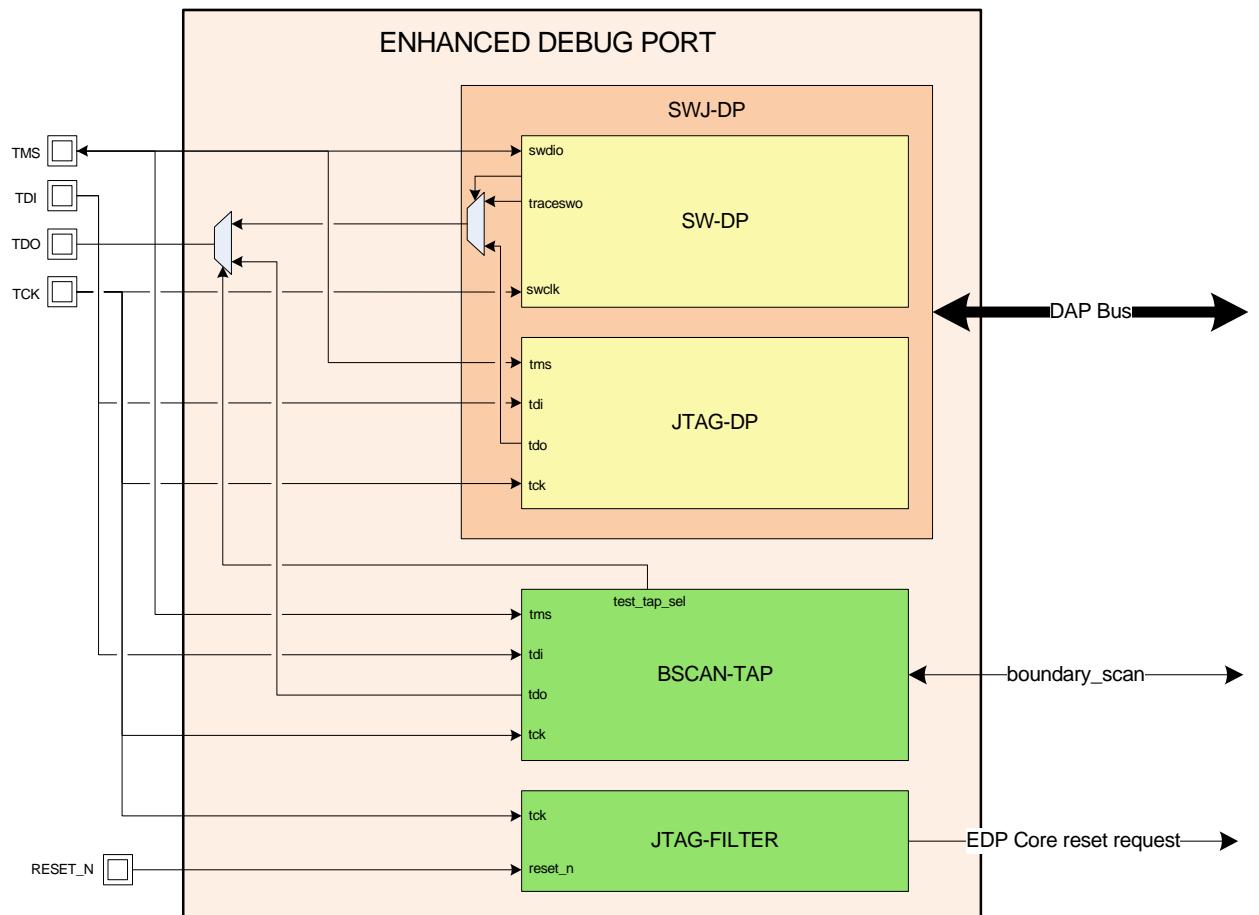


Figure 6-2. ATSAM4LC Power Domain Diagram



### 8.7.3 Block Diagram

**Figure 8-3.** Enhanced Debug Port Block Diagram



### 8.7.4 I/O Lines Description

**Table 8-1.** I/O Lines Description

Name	JTAG Debug Port		SWD Debug Port	
	Type	Description	Type	Description
TCK/SWCLK	I	Debug Clock	I	Serial Wire Clock
TDI	I	Debug Data in	-	NA
TDO/TRACESWO	O	Debug Data Out	O	Trace asynchronous Data Out
TMS/SWDIO	I	Debug Mode Select	I/O	Serial Wire Input/Output
RESET_N	I	Reset	I	Reset

1. Select the IR Scan path.
2. In Capture-IR: The IR output value is latched into the shift register.
3. In Shift-IR: The instruction register is shifted by the TCK input.
4. Return to Run-Test/Idle.
5. Select the DR Scan path.
6. In Capture-DR: The Data on the external pins are sampled into the boundary-scan chain.
7. In Shift-DR: The boundary-scan chain is shifted by the TCK input.
8. Return to Run-Test/Idle.

**Table 8-6.** SAMPLE\_PRELOAD Details

Instructions	Details
IR input value	<b>0001</b> (0x1)
IR output value	p00s
DR Size	Depending on boundary-scan chain, see BSDL-file.
DR input value	Depending on boundary-scan chain, see BSDL-file.
DR output value	Depending on boundary-scan chain, see BSDL-file.

#### 8.7.14.3 INTEST

This instruction selects the boundary-scan chain as Data Register for testing internal logic in the device. The logic inputs are determined by the boundary-scan chain, and the logic outputs are captured by the boundary-scan chain. The device output pins are driven from the boundary-scan chain.

Starting in Run-Test/Idle, the INTEST instruction is accessed the following way:

1. Select the IR Scan path.
2. In Capture-IR: The IR output value is latched into the shift register.
3. In Shift-IR: The instruction register is shifted by the TCK input.
4. In Update-IR: The data from the boundary-scan chain is applied to the internal logic inputs.
5. Return to Run-Test/Idle.
6. Select the DR Scan path.
7. In Capture-DR: The data on the internal logic is sampled into the boundary-scan chain.
8. In Shift-DR: The boundary-scan chain is shifted by the TCK input.
9. In Update-DR: The data from the boundary-scan chain is applied to internal logic inputs.
10. Return to Run-Test/Idle.

**Table 8-7.** INTEST Details

Instructions	Details
IR input value	<b>0100</b> (0x4)
IR output value	p001
DR Size	Depending on boundary-scan chain, see BSDL-file.
DR input value	Depending on boundary-scan chain, see BSDL-file.
DR output value	Depending on boundary-scan chain, see BSDL-file.

## 8.9.11.2 Status Register

**Name:** SR**Access Type:** Read-Only**Offset:** 0x04**Reset Value:** 0x00000000

31	30	29	28	27	26	25	24
-	-	-	-	-	STATE		
23	22	21	20	19	18	17	16
-	-	-	-	-	-	-	-
15	14	13	12	11	10	9	8
-	-	-	-	-	DBG	PROT	EN
7	6	5	4	3	2	1	0
-	-	-	LCK	FAIL	BERR	HCR	DONE

• **STATE: State**

Value	State	Description
0	IDLE	Idle state
1	CE	Chip erase operation is ongoing
2	CRC32	CRC32 operation is ongoing
3	FSPR	Flash User Page Read
4-7	-	reserved

• **DBG: Debugger present**

- 1: A debugger is present (TCK falling edge detected)
- 0: No debugger is present

• **PROT: Protected**

- 1: The protected state is set. The only way to overcome this is to issue a Chip Erase command.
- 0: The protected state is not set

• **EN: Enabled**

- 1: The block is in ready for operation
- 0: the block is disabled. Write operations are not possible until the block is enabled by writing a one in CR.EN.

• **LCK: Lock**

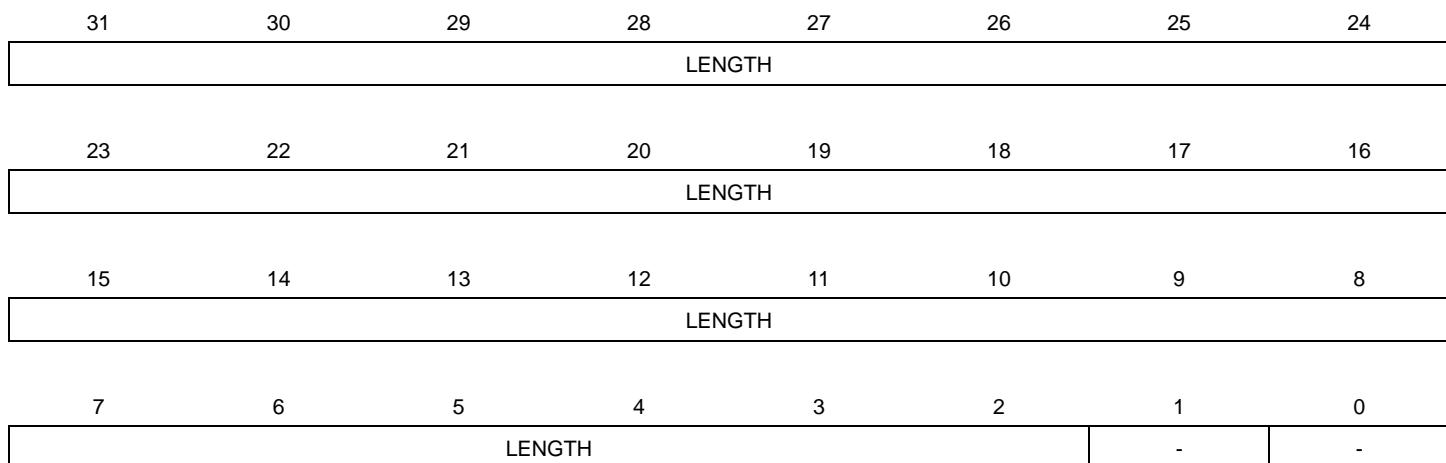
- 1: An operation could not be performed because chip protected state is on.
- 0: No security issues have been detected since last clear of this bit

• **FAIL: Failure**

- 1: The requested operation failed
- 0: No failure has been detected since last clear of this bit

• **BERR: Bus Error**

- 1: A bus error occurred due to the inability to access part of the requested memory area.

8.9.11.5 *Length Register***Name:** LENGTH**Access Type:** Read/Write**Offset:** 0x10**Reset Value:** 0x00000000

- **LENGTH:** Length Value, Bits 1-0 are always zero

**Table 9-5.** Maximum Clock Frequencies in Power Scaling Mode 1 and RUN Mode

Symbol	Parameter	Description	Max	Units
$f_{CPU}$	CPU clock frequency		12	MHz
$f_{PBA}$	PBA clock frequency		12	
$f_{PBB}$	PBB clock frequency		12	
$f_{PBC}$	PBC clock frequency		12	
$f_{PBD}$	PBD clock frequency		12	
$f_{GCLK0}$	GCLK0 clock frequency	DFLLIF main reference, GCLK0 pin	16.6	
$f_{GCLK1}$	GCLK1 clock frequency	DFLLIF dithering and SSGreference, GCLK1 pin	16.6	
$f_{GCLK2}$	GCLK2 clock frequency	AST, GCLK2 pin	6.6	
$f_{GCLK3}$	GCLK3 clock frequency	CATB, GCLK3 pin	17.3	
$f_{GCLK4}$	GCLK4 clock frequency	FLO and AESA	16.6	
$f_{GCLK5}$	GCLK5 clock frequency	GLOC, TC0 and RC32KIFB_REF	26.6	
$f_{GCLK6}$	GCLK6 clock frequency	ABDACB and IISC	16.6	
$f_{GCLK7}$	GCLK7 clock frequency	USBC	16.6	
$f_{GCLK8}$	GCLK8 clock frequency	TC1 and PEVC[0]	16.6	
$f_{GCLK9}$	GCLK9 clock frequency	PLL0 and PEVC[1]	16.6	
$f_{GCLK10}$	GCLK10 clock frequency	ADCIFE	16.6	
$f_{GCLK11}$	GCLK11 clock frequency	Master generic clock. Can be used as source for other generic clocks	51.2	
$f_{OSC0}$	OSC0 output frequency	Oscillator 0 in crystal mode	16	
		Oscillator 0 in digital clock mode	16	
$f_{PLL}$	PLL output frequency	Phase Locked Loop	N/A	
$f_{DFLL}$	DFLL output frequency	Digital Frequency Locked Loop	N/A	
$f_{RC80M}$	RC80M output frequency	Internal 80MHz RC Oscillator	N/A	

**Table 9-11.** Typical Current Consumption by Peripheral in Power Scaling Mode 0 and 2<sup>(1)</sup>

Peripheral	Typ Consumption Active	Unit
IISC	1.0	
SPI	1.9	
TC	6.3	
TWIM	1.5	
TWIS	1.2	
USART	8.5	
ADCIFE <sup>(2)</sup>	3.1	
DACC	1.3	
ACIFC <sup>(2)</sup>	3.1	
GLOC	0.4	
ABDACB	0.7	
TRNG	0.9	
PARC	0.7	
CATB	3.0	
LCDCA	4.4	
PDCA	1.0	
CRCCU	0.3	
USBC	1.5	
PEVC	5.6	
CHIPID	0.1	
SCIF	6.4	
FREQM	0.5	
GPIO	7.1	
BPM	0.9	
BSCIF	4.6	
AST	1.5	
WDT	1.4	
EIC	0.6	
PICOUART	0.3	

μA/MHz

1. These numbers are valid for the measured condition only and must not be extrapolated to other frequencies
2. Includes the current consumption on VDDANA and ADVREFP.

#### 9.5.4 .Peripheral Power Consumption in Power Scaling mode 1

The values in [Table 9-13](#) are measured values of power consumption under the following conditions:

## 9.6 I/O Pin Characteristics

### 9.6.1 Normal I/O Pin

**Table 9-13.** Normal I/O Pin Characteristics <sup>(1)</sup>

Symbol	Parameter	Conditions	Min	Typ	Max	Units
$R_{PULLUP}$	Pull-up resistance <sup>(2)</sup>			40		$\text{k}\Omega$
$R_{PULLDOWN}$	Pull-down resistance <sup>(2)</sup>			40		$\text{k}\Omega$
$V_{IL}$	Input low-level voltage		-0.3		$0.2 * V_{VDD}$	V
$V_{IH}$	Input high-level voltage		$0.8 * V_{VDD}$		$V_{VDD} + 0.3$	
$V_{OL}$	Output low-level voltage				0.4	
$V_{OH}$	Output high-level voltage		$V_{VDD} - 0.4$			
$I_{OL}$	Output low-level current <sup>(3)</sup>	ODCR0=0	1.68V < $V_{VDD}$ < 2.7V		0.8	mA
			2.7V < $V_{VDD}$ < 3.6V		1.6	
		ODCR0=1	1.68V < $V_{VDD}$ < 2.7V		1.6	mA
			2.7V < $V_{VDD}$ < 3.6V		3.2	
$I_{OH}$	Output high-level current <sup>(3)</sup>	ODCR0=0	1.68V < $V_{VDD}$ < 2.7V		0.8	mA
			2.7V < $V_{VDD}$ < 3.6V		1.6	
		ODCR0=1	1.68V < $V_{VDD}$ < 2.7V		1.6	mA
			2.7V < $V_{VDD}$ < 3.6V		3.2	
$t_{RISE}$	Rise time <sup>(2)</sup>	OSRR0=0	ODCR0=0 1.68V < $V_{VDD}$ < 2.7V, load = 25pF		35	ns
		OSRR0=1			45	
		OSRR0=0	ODCR0=0 2.7V < $V_{VDD}$ < 3.6V, load = 25pF		19	ns
		OSRR0=1			23	
$t_{FALL}$	Fall time <sup>(2)</sup>	OSRR0=0	ODCR0=0 1.68V < $V_{VDD}$ < 2.7V, load = 25pF		36	ns
		OSRR0=1			47	
		OSRR0=0	ODCR0=0 2.7V < $V_{VDD}$ < 3.6V, load = 25pF		20	ns
		OSRR0=1			24	
$F_{PINMAX}$	Output frequency <sup>(2)</sup>	OSRR0=0	ODCR0=0, $V_{VDD} > 2.7V$ load = 25pF		17	MHz
		OSRR0=1			15	MHz
		OSRR0=0	ODCR0=1, $V_{VDD} > 2.7V$ load = 25pF		27	MHz
		OSRR0=1			23	MHz
$I_{LEAK}$	Input leakage current <sup>(3)</sup>		Pull-up resistors disabled	0.01	1	$\mu\text{A}$
$C_{IN}$	Input capacitance <sup>(2)</sup>			5		pF

- $V_{VDD}$  corresponds to either  $V_{VDDIN}$  or  $V_{VDDIO}$ , depending on the supply for the pin. Refer to [Section 3-5 on page 13](#) for details
- These values are based on simulation. These values are not covered by test limits in production or characterization

## 9.6.3 USB I/O Pin : PA25, PA26

Table 9-15. USB I/O Pin Characteristics in GPIO configuration<sup>(1)</sup>

Symbol	Parameter	Conditions		Min	Typ	Max	Units
R <sub>PULLUP</sub>	Pull-up resistance <sup>(2)</sup>				40		kΩ
R <sub>PULLDOWN</sub>	Pull-down resistance <sup>(2)</sup>				40		kΩ
V <sub>IL</sub>	Input low-level voltage			-0.3		0.2 * V <sub>VDD</sub>	V
V <sub>IH</sub>	Input high-level voltage			0.8 * V <sub>VDD</sub>		V <sub>VDD</sub> + 0.3	
V <sub>OL</sub>	Output low-level voltage					0.4	
V <sub>OH</sub>	Output high-level voltage			V <sub>VDD</sub> - 0.4			
I <sub>OL</sub>	Output low-level current <sup>(3)</sup>	ODCR0=0	1.68V < V <sub>VDD</sub> < 2.7V		20		mA
			2.7V < V <sub>VDD</sub> < 3.6V		30		
I <sub>OH</sub>	Output high-level current <sup>(3)</sup>	ODCR0=0	1.68V < V <sub>VDD</sub> < 2.7V		20		mA
			2.7V < V <sub>VDD</sub> < 3.6V		30		
F <sub>PINMAX</sub>	Maximum frequency <sup>(2)</sup>	ODCR0=0 OSRR0=0	load = 25pF			20	MHz
I <sub>LEAK</sub>	Input leakage current <sup>(3)</sup>	Pull-up resistors disabled			0.01	1	μA
C <sub>IN</sub>	Input capacitance <sup>(2)</sup>				5		pF

1. V<sub>VDD</sub> corresponds to either V<sub>VDDIN</sub> or V<sub>VDDIO</sub>, depending on the supply for the pin. Refer to [Section 3-5 on page 13](#) for details

2. These values are based on simulation. These values are not covered by test limits in production or characterization

3. These values are based on characterization. These values are not covered by test limits in production

## 9.6.4 TWI Pin : PA21, PA22, PA23, PA24, PB14, PB15

Table 9-16. TWI Pin Characteristics in TWI configuration<sup>(1)</sup>

Symbol	Parameter	Conditions		Min	Typ	Max	Units
R <sub>PULLUP</sub>	Pull-up resistance <sup>(2)</sup>				40		kΩ
R <sub>PULLDOWN</sub>	Pull-down resistance <sup>(2)</sup>				40		kΩ
V <sub>IL</sub>	Input low-level voltage			-0.3		0.3 * V <sub>VDD</sub>	V
V <sub>IH</sub>	Input high-level voltage			0.7 * V <sub>VDD</sub>		V <sub>VDD</sub> + 0.3	V
V <sub>OL</sub>	Output low-level voltage					0.4	V
I <sub>OL</sub>	Output low-level current <sup>(3)</sup>			DRIVEL=0		0.5	mA
				DRIVEL=1		1.0	
				DRIVEL=2		1.6	
				DRIVEL=3		3.1	
				DRIVEL=4		6.2	
				DRIVEL=5		9.3	
				DRIVEL=6		15.5	
				DRIVEL=7		21.8	

**Table 9-17.** TWI Pin Characteristics in GPIO configuration<sup>(1)</sup>

Symbol	Parameter	Conditions		Min	Typ	Max	Units
$t_{RISE}$	Rise time <sup>(2)</sup>	OSRR0=0	ODCR0=0 1.68V < $V_{VDD}$ < 2.7V, Cload = 25pF		18		ns
		OSRR0=1			110		
		OSRR0=0	ODCR0=0 2.7V < $V_{VDD}$ < 3.6V, Cload = 25pF		10		ns
		OSRR0=1			50		
$t_{FALL}$	Fall time <sup>(2)</sup>	OSRR0=0	ODCR0=0 1.68V < $V_{VDD}$ < 2.7V, Cload = 25pF		19		ns
		OSRR0=1			140		
		OSRR0=0	ODCR0=0 2.7V < $V_{VDD}$ < 3.6V, Cload = 25pF		12		ns
		OSRR0=1			63		

1.  $V_{VDD}$  corresponds to either  $V_{VDDIN}$  or  $V_{VDDIO}$ , depending on the supply for the pin. Refer to [Section 3-5 on page 13](#) for details

2. These values are based on simulation. These values are not covered by test limits in production or characterization

3. These values are based on characterization. These values are not covered by test limits in production

**Table 9-18.** Common TWI Pin Characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Units
$I_{LEAK}$	Input leakage current <sup>(1)</sup>	Pull-up resistors disabled		0.01	1	$\mu A$
$C_{IN}$	Input capacitance <sup>(2)</sup>			5		$pF$

1. These values are based on simulation. These values are not covered by test limits in production or characterization

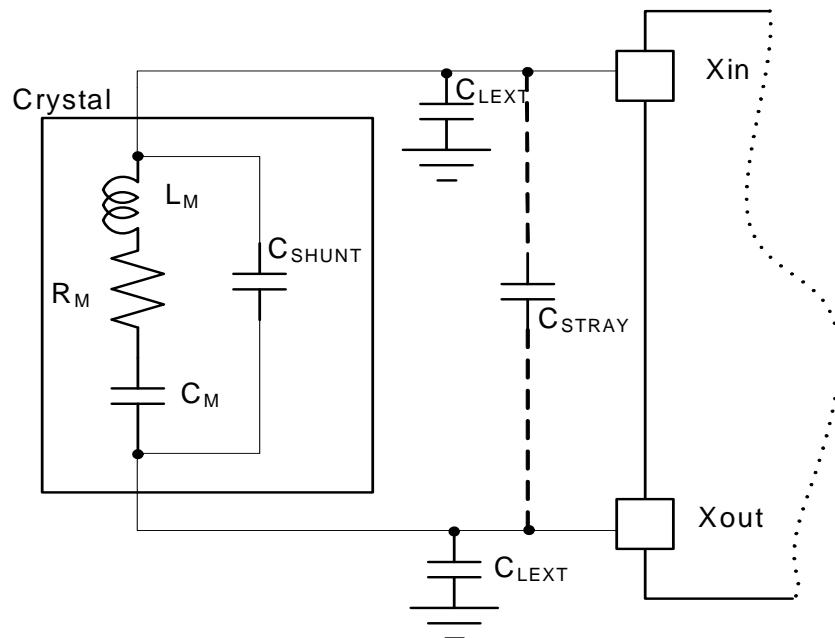
**Table 9-23.** Crystal Oscillator Characteristics

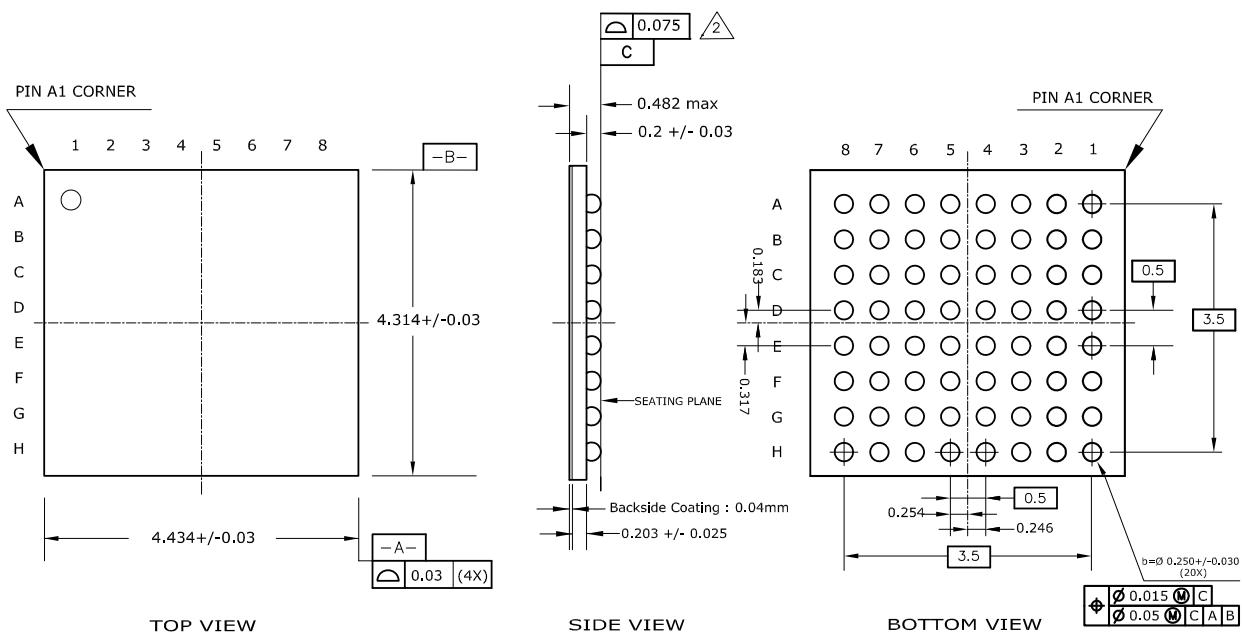
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$C_L$	Crystal load capacitance <sup>(1)</sup>	TQFP100 package	6		18	pF
$C_{SHUNT}$	Crystal shunt capacitance <sup>(1)</sup>				7	
$C_{XIN}$	Parasitic capacitor load <sup>(2)</sup>			4.91		
$C_{XOUT}$	Parasitic capacitor load <sup>(2)</sup>			3.22		
$t_{STARTUP}$	Startup time <sup>(1)</sup>	SCIF.OSCCTRL.GAIN = 2		30000 <sup>(3)</sup>		cycles
$I_{osc}$	Current consumption <sup>(1)</sup>	Active mode, $f = 0.6\text{MHz}$ , SCIF.OSCCTRL.GAIN = 0		30		$\mu\text{A}$
		Active mode, $f = 4\text{MHz}$ , SCIF.OSCCTRL.GAIN = 1		130		
		Active mode, $f = 8\text{MHz}$ , SCIF.OSCCTRL.GAIN = 2		260		
		Active mode, $f = 16\text{MHz}$ , SCIF.OSCCTRL.GAIN = 3		590		
		Active mode, $f = 30\text{MHz}$ , SCIF.OSCCTRL.GAIN = 4		960		

1. These values are based on simulation. These values are not covered by test limits in production or characterization.

2. These values are based on characterization. These values are not covered by test limits in production.

3. Nominal crystal cycles.

**Figure 9-3.** Oscillator Connection

**Figure 10-3.** WLCSP64 SAM4LC4/2 Package Drawing

Notes : 1. Dimension "b" is measured at the maximum ball diameter in a plane to the seating plane.

2. Applied to whole wafer.

**Table 10-8.** Device and Package Maximum Weight

14.8	mg
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**Table 10-9.** Package Characteristics

Moisture Sensitivity Level	MSL3
----------------------------	------

**Table 10-10.** Package Reference

JEDEC Drawing Reference	MS-026
JESD97 Classification	E1

**Table 11-5.** ATSAM4LS4 Sub Serie Ordering Information

Ordering Code	Flash (Kbytes)	RAM (Kbytes)	Package	Conditioning	Package Type	Temperature Operating Range
ATSAM4LS4CA-AU-ES	256	32	TQFP100	ES	Green	N/A
ATSAM4LS4CA-AU				Tray		Industrial -40°C to 85°C
ATSAM4LS4CA-AUR				Reel		
ATSAM4LS4CA-CFU			VFBGA100	Tray		Industrial -40°C to 85°C
ATSAM4LS4CA-CFUR				Reel		
ATSAM4LS4BA-AU-ES			TQFP64	ES		N/A
ATSAM4LS4BA-AU				Tray		Industrial -40°C to 85°C
ATSAM4LS4BA-AUR				Reel		
ATSAM4LS4BA-MU-ES			QFN64	ES		N/A
ATSAM4LS4BA-MU				Tray		Industrial -40°C to 85°C
ATSAM4LS4BA-MUR				Reel		
ATSAM4LS4BA-UUR			WLCSP64	Reel		Industrial -40°C to 85°C
ATSAM4LS4AA-AU-ES			TQFP48	ES		N/A
ATSAM4LS4AA-AU				Tray		Industrial -40°C to 85°C
ATSAM4LS4AA-AUR				Reel		
ATSAM4LS4AA-MU-ES			QFN48	ES		N/A
ATSAM4LS4AA-MU				Tray		Industrial -40°C to 85°C
ATSAM4LS4AA-MUR				Reel		

**Table 11-6.** ATSAM4LS2 Sub Serie Ordering Information

Ordering Code	Flash (Kbytes)	RAM (Kbytes)	Package	Conditioning	Package Type	Temperature Operating Range
ATSAM4LS2CA-AU	128	32	TQFP100	Tray	Green	Industrial -40°C to 85°C
ATSAM4LS2CA-AUR				Reel		
ATSAM4LS2CA-CFU			VFBGA100	Tray		
ATSAM4LS2CA-CFUR				Reel		
ATSAM4LS2BA-AU			TQFP64	Tray		
ATSAM4LS2BA-AUR				Reel		
ATSAM4LS2BA-MU			QFN64	Tray		
ATSAM4LS2BA-MUR				Reel		
ATSAM4LS2BA-UUR			WLCSP64	Reel		
ATSAM4LS2AA-AU			TQFP48	Tray		
ATSAM4LS2AA-AUR				Reel		
ATSAM4LS2AA-MU			QFN48	Tray		
ATSAM4LS2AA-MUR				Reel		

## 12. Errata

### 12.1 ATSAM4L4 /2 Rev. B & ATSAM4L8 Rev. A

#### 12.1.1 General

##### **PS2 mode is not supported by Engineering Samples**

PS2 mode support is supported only by parts with calibration version higher than 0.

##### **Fix/Workaround**

The calibration version can be checked by reading a 32-bit word at address 0x0080020C. The calibration version bitfield is 4-bit wide and located from bit 4 to bit 7 in this word. Any value higher than 0 ensures that the part supports the PS2 mode

#### 12.1.2 SCIF

##### **PLLCOUNT value larger than zero can cause PLLEN glitch**

Initializing the PLLCOUNT with a value greater than zero creates a glitch on the PLLEN signal during asynchronous wake up.

##### **Fix/Workaround**

The lock-masking mechanism for the PLL should not be used.

The PLLCOUNT field of the PLL Control Register should always be written to zero.

#### 12.1.3 WDT

##### **WDT Control Register does not have synchronization feedback**

When writing to the Timeout Prescale Select (PSEL), Time Ban Prescale Select (TBAN), Enable (EN), or WDT Mode (MODE) fields of the WDT Control Register (CTRL), a synchronizer is started to propagate the values to the WDT clock domain. This synchronization takes a finite amount of time, but only the status of the synchronization of the EN bit is reflected back to the user. Writing to the synchronized fields during synchronization can lead to undefined behavior.

##### **Fix/Workaround**

- When writing to the affected fields, the user must ensure a wait corresponding to 2 clock cycles of both the WDT peripheral bus clock and the selected WDT clock source.

- When doing writes that changes the EN bit, the EN bit can be read back until it reflects the written value.

#### 12.1.4 SPI

##### **SPI data transfer hangs with CSR0.CSAAT==1 and MR.MODFDIS==0**

When CSR0.CSAAT==1 and mode fault detection is enabled (MR.MODFDIS==0), the SPI module will not start a data transfer.

##### **Fix/Workaround**

Disable mode fault detection by writing a one to MR.MODFDIS.

##### **SPI disable does not work in SLAVE mode**

SPI disable does not work in SLAVE mode.

## 13. Datasheet Revision History

Note that the referring page numbers in this section are referred to this document. The referring revision in this section are referring to the document revision.

### 13.1 Rev. A – 09/12

1. Initial revision.

### 13.2 Rev. B – 10/12

1. Fixed ordering code
2. Changed BOD18CTRL and BOD33CTRL ACTION field from "Reserved" to 'No action'

### 13.3 Rev. C – 02/13

1. Fixed ball pitch for VFBGA100 package
2. Added VFBGA100 and WLCSP64 pinouts
3. Added Power Scaling Mode 2 for high frequency support
4. Minor update on several modules chapters
5. Major update on Electrical characteristics
6. Updated errata
7. Fixed GPIO multiplexing pin numbers

### 13.4 Rev. D – 03/13

1. Removed WLCSP package information
2. Added errata text for detecting whether a part supports PS2 mode or not
3. Removed temperature sensor feature (not supported by production flow)
4. Fixed MUX selection on Positive ADC input channel table
5. Added information about TWI instances capabilities
6. Added some details on errata [Corrupted data in flash may happen after flash page write operations.<sup>171</sup>](#)

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13.5	Rev. E – 07/13 .....	173
13.6	Rev. F – 12/13 .....	173
13.7	Rev. G – 03/14 .....	173
13.8	Rev. H – 11/16 .....	173

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